

Search Notes

Application/Control No.

10/798,365

Examiner

John S. Chu

Applicant(s)/Patent under
Reexamination

TAKAMIYA

Art Unit

1752

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|--------|----------|
| 430 | 331 | 9/2006 | JSC |
| 430 | 270.1 | | |
| 430 | 302 | | |
| 101 | 465 | | |
| 101 | 467 | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|---------|--------|------|
| updated | 9/2006 | JSC |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |
| | | |

INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
|-------|-----------|--------|----------|
| 430 | 331,270.1 | 9/2006 | JSC |
| 430 | 302 | | |
| 101 | 465,467 | L | L |
| | | | |
| | | | |
| | | | |
| | | | |
| | | | |